



**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of:

Boyd et al

Serial No. 10/606,022

Filed: June 24, 2003

For: SYSTEM AND METHOD  
FOR INTEGRATING IN-SITU  
METROLOGY WITHIN A  
WAFER PROCESS

Examiner: PERRIN, J.

Art Unit: 1746

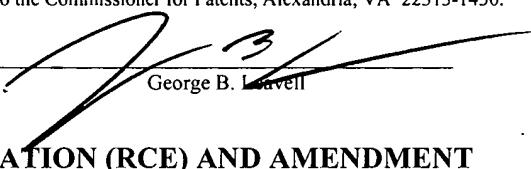
Atty Docket No. LAM2P425

Date: March 21, 2007

**CERTIFICATE OF MAILING**

I hereby certify that this paper and the documents and/or fees referred to as attached herein are being deposited with the United States Postal Service on **March 21, 2007** in an envelope as "Express Mail Post Office to Addressee" service under 37 CFR § 1.10, Mailing Label Number **EV979848149 US** addressed to the Commissioner for Patents, Alexandria, VA 22313-1450.

Signed:



George B. Leavell

**REQUEST FOR CONTINUED EXAMINATION (RCE) AND AMENDMENT**  
**AND RESPONSE TO ADVISORY ACTION**

Commissioner for Patents  
Alexandria, VA 22313-1450

In response to the Advisory Action mailed February 21, 2007, Applicant hereby requests an RCE under 37 CFR 1.114. Applicant also requests the following amendments be entered and the following remarks be considered.

Amendments to the Specification begin on page 2 of this paper.

A complete listing of claims with their current status begins on page 3 of this paper.

Remarks begin on page 7 of this paper.

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